ON Semiconductor

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Operational Amplifiers, High Slew Rate, Low Voltage, Rail-to-Rail Output

The NCS2003 family of op amps features high slew rate, low voltage operation with rail-to-rail output drive capability. The 1.8 V operation allows high performance operation in low voltage, low power applications. The fast slew rate and wide unity-gain bandwidth (5 MHz at 1.8 V) make these op amps suited for high speed applications. The low input offset voltage (4 mV max) allows the op amp to be used for current shunt monitoring. Additional features include no output phase reversal with overdriven inputs and ultra low input bias current of 1 pA.

The NCS2003 family is the ideal solution for a wide range of applications and products. The single channel NCS2003, dual channel NCS20032, and quad channel NCS20034 are available in a variety of compact and space-saving packages. The NCV prefix denotes that the device is AEC-Q100 Qualified and PPAP Capable.

Features

- Unity Gain Bandwidth: 7 MHz at $V_S = 5 \text{ V}$
- Fast Slew Rate: 8 V/ μ s rising, 12.5 V/ μ s falling at V_S = 5 V
- Rail-to-Rail Output
- No Output Phase Reversal for Over–Driven Input Signals
- Low Offset Voltage: 0.5 mV typical
- Low Input Bias Current: 1 pA typical
- NCV Prefix for Automotive and Other Applications Requiring Unique Site and Control Change Requirements; AEC-Q100 Qualified and PPAP Capable
- These Devices are Pb-Free, Halogen Free/BFR Free and are RoHS Compliant

Applications

- Current Shunt Monitor
- Signal Conditioning
- Active Filter
- Sensor Buffer

End Products

- Motor Control Drives
- Hard Drives
- Medical Devices
- White Goods and Air Conditioners



ON Semiconductor®

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SOT23-5 **CASE 483** (NCS/NCV2003)



SOT553, 5 LEAD CASE 463B (NCS2003)



Micro8™ **DM SUFFIX CASE 846A**



SOIC-8 **CASE 751**



TSSOP-8 **T SUFFIX CASE 948S**



SOIC-14 NB **CASE 751A**

















= Assembly Location

WL, L = Wafer Lot = Year WW, W = Work Week

G or ■ = Pb-Free Package

(Note: Microdot may be in either location)

ORDERING INFORMATION

See detailed ordering, marking and shipping information on page 2 of this data sheet.

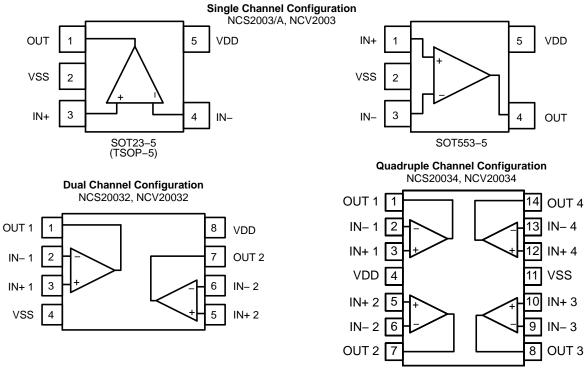


Figure 1. Pin Connections

ORDERING INFORMATION

Device	Configuration	Automotive	Marking	Package	Shipping [†]
NCS2003SN2T1G	Single	No	AN3	SOT23-5 (Pb-Free)	3000 / Tape and Reel
NCS2003ASN2T1G		No	AN4	SOT23-5 (Pb-Free)	3000 / Tape and Reel
NCS2003XV53T2G		No	А3	SOT553-5 (Pb-Free)	4000 /Tape and Reel
NCV2003SN2T1G*	7	Yes	AN3	SOT23-5 (Pb-Free)	3000 / Tape and Reel
NCS20032DMR2G	Dual	No	2K32	Micro8 (Pb-Free)	4000 / Tape and Reel
NCS20032DR2G			20032	SOIC-8 (Pb-Free)	2500 / Tape and Reel
NCS20032DTBR2G			K32	TSSOP-8 (Pb-Free)	3000 / Tape and Reel
NCV20032DMR2G*		Yes	2K32	Micro8 (Pb-Free)	4000 / Tape and Reel
NCV20032DR2G*			20032	SOIC-8 (Pb-Free)	2500 / Tape and Reel
NCV20032DTBR2G*			K32	TSSOP-8 (Pb-Free)	3000 / Tape and Reel
NCS20034DR2G	Quad	No	NCS20034G	SOIC-14 (Pb-Free)	2500 / Tape and Reel
NCV20034DR2G*		Yes	NCS20034G	SOIC-14 (Pb-Free)	2500 / Tape and Reel

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D

^{*}NCV Prefix for Automotive and Other Applications Requiring Unique Site and Control Change Requirements; AEC-Q100 Qualified and PPAP Capable.

ABSOLUTE MAXIMUM RATINGS

Over operating free-air temperature, unless otherwise stated

Parameter		Symbol	Limit	Unit
Supply Voltage (V _{DD} – V _{SS})		V _S	7.0	V
INPUT AND OUTPUT PINS				
Input Voltage (Note 1)		V _{IN}	V _{SS} – 0.3 to 7.0	V
Input Current		I _{IN}	10	mA
Output Short Current (Note 2)		Io	100	mA
TEMPERATURE				
Storage Temperature		T _{STG}	-65 to 150	°C
Junction Temperature		TJ	150	°C
ESD RATINGS (Note 3)				
Human Body Model	NCx2003, A NCx20032 NCx20034	НВМ	3000 2000 3000	V
Machine Model	NCx2003, A NCx20032 NCx20034	MM	200 100 150	V
Charged Device Model	NCx2003, A NCx2003x	CDM	1000 2000	V
OTHER PARAMETERS				•
Moisture Sensitivity Level (Note 5)		MSL	Level 1	
Latch-up Current (Note 4)		I _{LU}	100	mA

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

- Neither input should exceed the range of V_{SS} 300 mV to 7.0 V. This device contains internal protection diodes between the input pins and V_{DD}. When V_{IN} exceeds V_{DD}, the input current should be limited to the specified value.
- Indefinite duration; however, maximum package power dissipation limits must be observed to ensure that the maximum junction temperature is not exceeded.
- 3. This device series incorporates ESD protection and is tested by the following methods:
 - ESD Human Body Model tested per AEC-Q100-002 and JESD22-A114
 - ESD Machine Model tested per AEC-Q100-003 and JESD22-A115
 - ESD Charged Device Model tested per AEC-Q100-011 and ANSI/ESD S5.3.1-2009
- 4. Latch-up current tested per JEDEC Standard JESD78.
- 5. Moisture Sensitivity Level tested per IPC/JEDEC standard J-STD-020A.

THERMAL INFORMATION

Thermal Metric	Symbol	Package	Single Layer Board (Note 6)	Multi Layer Board (Note 7)	Unit
		SOT23-5/TSOP-5	408	355	
	Ambient esistance θ _{JA} Micro8/MSO SOIC-8 TSSOP-8	SOT553-5	428	406	
Junction to Ambient		Micro8/MSOP8	235	163	°C/W
Thermal Resistance		SOIC-8	240	179	°C/VV
		TSSOP-8	300	238	
		SOIC-14	167	123	

- Values based on a 1S standard PCB according to JEDEC51-3 with 1.0 oz copper and a 300 mm² copper area
- 7. Values based on a 1S2P standard PCB according to JEDEC51-7 with 1.0 oz copper and a 100 mm² copper area

RECOMMENDED OPERATING CONDITIONS

Paramet	er	Symbol	Min	Max	Unit
Operating Supply Voltage (V _{DD} – V _{SS})		V _S	1.7	5.5	V
Specified Operating Range	NCS2003, A NCV2003, NCx20032, NCx20034	T _A	-40 -40	+85 +125	°C
Input Common Mode Range		V_{CM}	V _{SS}	V _{DD} -0.6	V

Functional operation above the stresses listed in the Recommended Operating Ranges is not implied. Extended exposure to stresses beyond the Recommended Operating Ranges limits may affect device reliability.

ELECTRICAL CHARACTERISTICS: $V_S = +1.8 \text{ V}$

At T_A = +25°C, R_L = 10 k Ω connected to midsupply, V_{CM} = V_{OUT} = midsupply, unless otherwise noted. **Boldface** limits apply over the specified temperature range. Guaranteed by design and/or characterization.

INPUT CHARACTERISTICS Input Offset Voltage							
Input Offset Voltage					-		
	Vos	NCS2003A			0.5	3.0	mV
		NCx2003, NCx20032,	NCx20034		0.5	4.0	mV
						5.0	mV
Offset Voltage Drift	$\Delta V_{OS}/\Delta T$				2.0		μV/°C
		NCS2003A (Not	e 8)			6.0	μV/°C
Input Bias Current	I _{IB}				1		рА
Input Offset Current	I _{OS}				1		рА
Channel Separation	XTLK	DC, NCx20032, NC	x20034		100		dB
Input Resistance	R _{IN}				1		TΩ
Input Capacitance	C _{IN}				1.2		pF
Common Mode Rejection	CMRR	$V_{IN} = V_{SS}$ to V_{DD} -	- 0.6 V	70	80		dB
Ratio		$V_{IN} = V_{SS} + 0.2 \text{ V to V}$	_{DD} – 0.6 V	65			
OUTPUT CHARACTERISTIC	S						
Open Loop Voltage Gain	A _{VOL}	$R_L = 10 \text{ k}\Omega$		80	92		dB
				75			
		$R_L = 2 k\Omega$			92		
				70			
Output Current Capability	I _{SC}	Sourcing		5	8		mA
(Note 8)		Sinking		10	14		
Output Voltage High	V _{OH}	$R_L = 10 \text{ k}\Omega$		1.75	1.798		V
		$R_L = 2 k\Omega$		1.7	1.78		
Output Voltage Low	Vol	$R_L = 10 \text{ k}\Omega$	NCx2003, A		7	50	mV
			NCx2003x		7	100	
		$R_L = 2 k\Omega$			20	100	
NOISE PERFORMANCE							
Voltage Noise Density	e _N	f = 1 kHz			20		nV/√ Hz
Current Noise Density	i _N	f = 1 kHz			0.1		pA√ Hz
DYNAMIC PERORMANCE							
Gain Bandwidth Product	GBWP				5		MHz
Olassa Data at Haita Oaia	OD	Rising Edge, R _L = 2 ks	2, A _V = +1		6		\// -
Slew Rate at Unity Gain	SR	Falling Edge, $R_L = 2 \text{ k}\Omega$, $A_V = +1$			9		V/μs
Phase Margin	ψm	$R_L = 10 \text{ k}\Omega, C_L =$	5 pF		53		0
Gain Margin	A _m	$R_L = 10 \text{ k}\Omega$, $C_L = 5 \text{ pF}$	NCx2003, A		12		dB
			NCx2003x		8		
Settling Time	ts	$V_O = 1 \text{ Vpp},$ Gain = 1, $C_L = 20 \text{ pF}$	Settling time to 0.1%		1.8		μS

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

^{8.} Guaranteed by design and/or characterization.

ELECTRICAL CHARACTERISTICS: V_S = +1.8 V

At $T_A = +25^{\circ}C$, $R_L = 10 \text{ k}\Omega$ connected to midsupply, $V_{CM} = V_{OUT} = \text{midsupply}$, unless otherwise noted. **Boldface** limits apply over the specified temperature range. Guaranteed by design and/or characterization.

Parameter	Symbol	Conditions		Min	Тур	Max	Unit
DYNAMIC PERORMANCE				•	•		
Total Harmonics Distortion +	THD+N	$V_O = 1 V_{pp}, R_L = 2 k\Omega, A_V$	= +1, f = 1 kHz		0.005		%
Noise		$V_O = 1 V_{pp}, R_L = 2 k\Omega, A_V$	= +1, f = 10 kHz		0.025		
POWER SUPPLY							
Power Supply Rejection Ratio	PSRR	NCx2003		72	80		dB
				65			
		NCx20032, NCx	20034	80	100		
Quiescent Current	I _{DD}	No load, per channel	NCx2003, A		230	560	μΑ
						1000	
NCx20032, NCx20034					275	375	
				575			

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

8. Guaranteed by design and/or characterization.

ELECTRICAL CHARACTERISTICS: V_S = +5.0 V

At $T_A = +25^{\circ}$ C, $R_L = 10 \text{ k}\Omega$ connected to midsupply, $V_{CM} = V_{OUT} = \text{midsupply}$, unless otherwise noted. **Boldface** limits apply over the specified temperature range. Guaranteed by design and/or characterization.

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
INPUT CHARACTERISTICS	S					
Input Offset Voltage	V _{OS}	NCS2003A		0.5	3.0	mV
		NCx2003		0.5	4.0	mV
		NCx20032, NCx20034			5.0	mV
Offset Voltage Drift	ΔV _{OS} /ΔT			2.0		μV/°C
		NCS2003A (Note 9)			6.0	μV/°C
Input Bias Current	I _{IB}			1		рА
Input Offset Current	I _{OS}			1		рА
Channel Separation	XTLK	DC, NCx20032, NCx20034		100		dB
Input Resistance	R _{IN}			1		TΩ
Input Capacitance	C _{IN}			1.2		pF

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

9. Guaranteed by design and/or characterization.

ELECTRICAL CHARACTERISTICS: V_S = +5.0 V

At $T_A = +25^{\circ}C$, $R_L = 10 \text{ k}\Omega$ connected to midsupply, $V_{CM} = V_{OUT} = \text{midsupply}$, unless otherwise noted. **Boldface** limits apply over the specified temperature range. Guaranteed by design and/or characterization.

Parameter	Symbol	Conditi	ons	Min	Тур	Max	Unit
INPUT CHARACTERISTICS							•
Common Mode Rejection Ratio	CMRR	NCx2003, A	$V_{IN} = V_{SS}$ to $V_{DD} - 0.6$ V	65	90		dB
			$V_{IN} = V_{SS} + 0.2 \text{ V}$ to $V_{DD} - 0.6 \text{ V}$	63			
		NCx20032, NCx20034	$V_{IN} = V_{SS}$ to $V_{DD} - 0.6$ V	70	90		
			$V_{IN} = V_{SS} + 0.2 \text{ V}$ to $V_{DD} - 0.6 \text{ V}$	65			
OUTPUT CHARACTERISTICS							
Open Loop Voltage Gain	A _{VOL}	R _L = 10	kΩ	86	92		dB
				78			
		R _L = 2	$R_L = 2 k\Omega$		92		
				78			
Output Current Capability	I _{SC}	Sourcing Sinking		40	76		mA
(Note 9)				50	96		
Output Voltage High	V _{OH}	$R_L = 10 \text{ k}\Omega$		4.95	4.99		V
		R _L = 2	kΩ	4.9	4.97		
Output Voltage Low	Vol	$R_L = 10 \text{ k}\Omega$	NCx2003, A		8	50	mV
			NCx2003x		8	100	
		R _L = 2	kΩ		24	100	
NOISE PERFORMANCE							
Voltage Noise Density	e _N	f = 1 k	Hz		20		nV/√ Hz
Current Noise Density	i _N	f = 1 k	Hz		0.1		pA√ Hz
DYNAMIC PERORMANCE							
Gain Bandwidth Product	GBWP				7		MHz
Slew Rate at Unity Gain	SR	Rising Edge, R _L =	2 k Ω , AV = +1		8		V/μs
		Falling Edge, R _L =	2 kΩ, AV = +1		12.5		
Phase Margin	Ψm	$R_L = 10 \text{ k}\Omega$, $C_L = 5 \text{ pF}$	NCx2003, A		64		۰
			NCx2003x		56		
Gain Margin	A _m	$R_L = 10 \text{ k}\Omega$, (C _L = 5 pF		9		dB
Settling Time	t _S	$V_{O} = 1 V_{pp},$ Gain = 1, $C_{L} = 20 pF$	Settling time to 0.1%		0.6		μs
Total Harmonics Distortion +	THD+N	$V_O = 4 V_{pp}, R_L = 2 k\Omega,$	$A_V = +1, f = 1 \text{ kHz}$		0.002		%
Noise		$V_O = 4 V_{pp}, R_L = 2 k\Omega,$	$A_V = +1, f = 10 \text{ kHz}$		0.01		

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

9. Guaranteed by design and/or characterization.

ELECTRICAL CHARACTERISTICS: $V_S = +5.0 \text{ V}$

At $T_A = +25^{\circ}C$, $R_L = 10 \text{ k}\Omega$ connected to midsupply, $V_{CM} = V_{OUT} = \text{midsupply}$, unless otherwise noted. **Boldface** limits apply over the specified temperature range. Guaranteed by design and/or characterization.

Parameter	Symbol	Conditions		Min	Тур	Max	Unit
POWER SUPPLY							
Power Supply Rejection Ratio	PSRR	NCx2003, A NCx20032, NCx20034		72	80		dB
				65			
				80	100		
Quiescent Current	I _{DD}	No load, per channel	NCx2003, A		300	660	μΑ
						1000	
		NCx20032,			325	450	
			NCx20034			675	

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

^{9.} Guaranteed by design and/or characterization.

TYPICAL CHARACTERISTICS

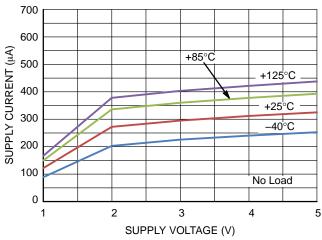


Figure 2. Quiescent Supply Current vs. Supply Voltage

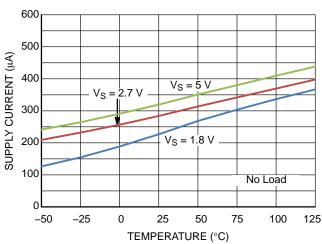


Figure 3. Quiescent Supply Current vs.
Temperature

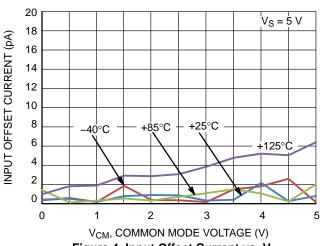


Figure 4. Input Offset Current vs. V_{CM}

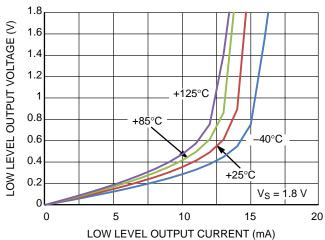


Figure 5. Low Level Output Voltage vs. Output Current @ $V_S = 1.8 \text{ V}$

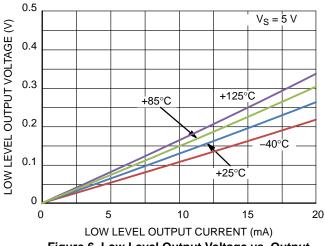


Figure 6. Low Level Output Voltage vs. Output Current @ $V_S = 5 V$

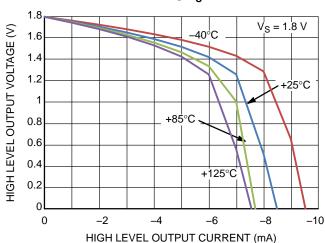


Figure 7. High Level Output Voltage vs. Output Current @ V_S = 1.8 V

TYPICAL CHARACTERISTICS

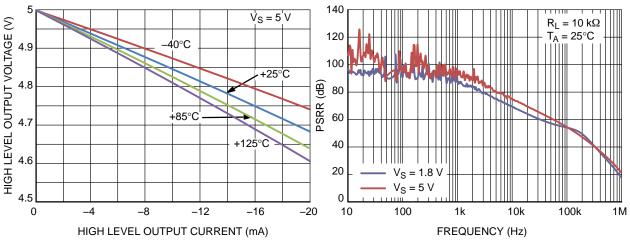


Figure 8. High Level Output Voltage vs. Output Current @ $V_S = 5 V$

Figure 9. PSRR vs. Frequency

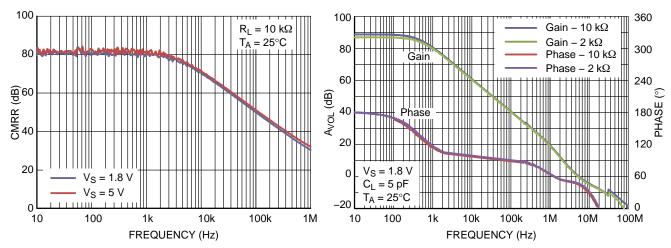


Figure 10. CMRR vs. Frequency

Figure 11. Open Loop Gain and Phase vs. Frequency @ $V_S = 1.8 \text{ V}$

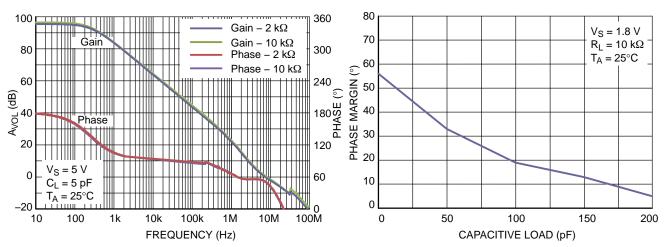
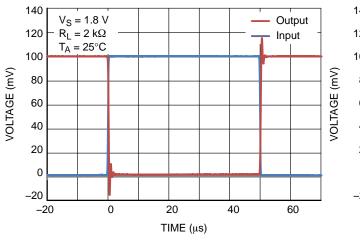


Figure 12. Open Loop Gain and Phase vs. Frequency @ V_S = 5 V

Figure 13. Phase Margin vs. Capacitive Load

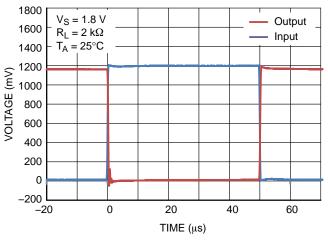
TYPICAL CHARACTERISTICS



Output $V_S = 1.8 V$ $R_L = 2 k\Omega$ 120 Input $T_A = 25^{\circ}C$ 100 80 60 40 20 0 -20 20 40 0 60 -20TIME (µs)

Figure 14. Inverting Small Signal Transient Response

Figure 15. Non-Inverting Small Signal Transient Response



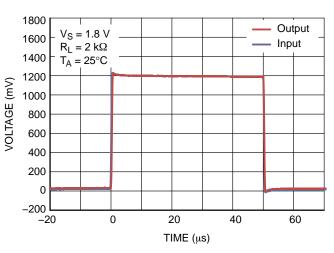
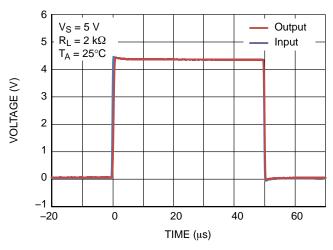


Figure 16. Inverting Large Signal Transient Response

Figure 17. Non-Inverting Large Signal Transient Response



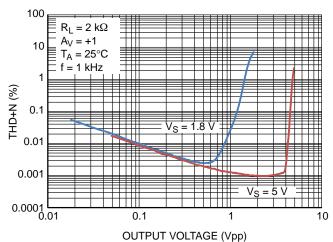
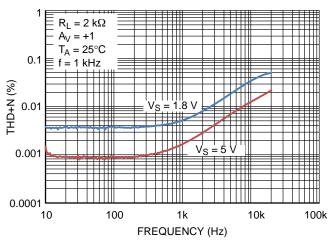


Figure 18. Non-Inverting Large Signal Transient Response

Figure 19. THD+N vs. Output Voltage

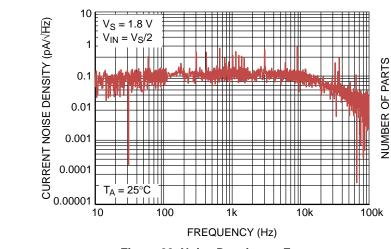
TYPICAL CHARACTERISTICS



140 120 VOLTAGE NOISE (nV√Hz) = 25°C 100 80 60 40 20 0 10 100 1k 10k 100k FREQUENCY (Hz)

Figure 20. THD+N vs. Frequency

Figure 21. Input Voltage Noise vs. Frequency



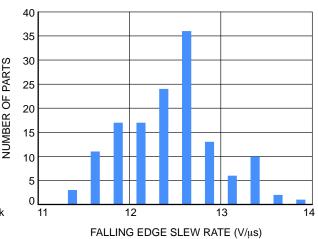
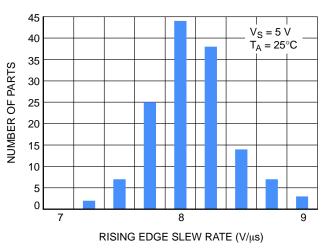


Figure 22. Noise Density vs. Frequency

Figure 23. Falling Edge Slew Rate @ Vs = 5 V



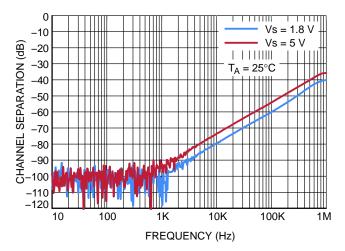


Figure 24. Rising Edge Slew Rate @ Vs = 5 V

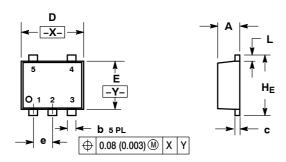
Figure 25. Channel Separation

Micro8 is a trademark of International Rectifier.

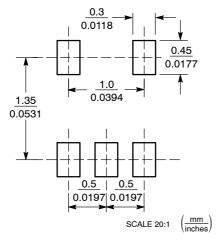


SOT-553, 5 LEAD CASE 463B **ISSUE C**

DATE 20 MAR 2013



RECOMMENDED SOLDERING FOOTPRINT*



*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

5. COLLECTOR

5. COLLECTOR 2/BASE 1

NOTES:

- NOTES:

 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.

 2. CONTROLLING DIMENSION: MILLIMETERS

 3. MAXIMUM LEAD THICKNESS INCLUDES LEAD FINISH
 THICKNESS: MINIMUM LEAD THICKNESS IS THE MINIMUM
 THICKNESS OF BASE MATERIAL.

	М	ILLIMETE	RS	INCHES			
DIM	MIN	NOM	MAX	MIN	NOM	MAX	
Α	0.50	0.55	0.60	0.020	0.022	0.024	
b	0.17	0.22	0.27	0.007	0.009	0.011	
С	0.08	0.13	0.18	0.003	0.005	0.007	
D	1.55	1.60	1.65	0.061	0.063	0.065	
E	1.15	1.20	1.25	0.045	0.047	0.049	
е		0.50 BSC			0.020 BSC		
L	0.10	0.20	0.30	0.004	0.008	0.012	
He	1.55	1.60	1 65	0.061	0.063	0.065	

GENERIC MARKING DIAGRAM*



XX = Specific Device Code

M = Date Code

= Pb-Free Package

(Note: Microdot may be in either location)

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot " ■", may or may not be present.

STYLE 1: PIN 1. BASE 2. EMITTER 3. BASE 4. COLLECTOR 5. COLLECTOR	STYLE 2: PIN 1. CATHODE 2. COMMON ANODE 3. CATHODE 2 4. CATHODE 3 5. CATHODE 4	STYLE 3: PIN 1. ANODE 1 2. N/C 3. ANODE 2 4. CATHODE 2 5. CATHODE 1	STYLE 4: PIN 1. SOURCE 1 2. DRAIN 1/2 3. SOURCE 1 4. GATE 1 5. GATE 2	STYLE 5: PIN 1. ANODE 2. EMITTER 3. BASE 4. COLLECTOR 5. CATHODE
STYLE 6:	STYLE 7:	STYLE 8:	STYLE 9:	
PIN 1. EMITTER 2	PIN 1. BASE	PIN 1. CATHODE	PIN 1. ANODE	
2. BASE 2	2. EMITTER	2. COLLECTOR	2. CATHODE	
3. EMITTER 1	3. BASE	3. N/C	3. ANODE	
4. COLLECTOR 1	4. COLLECTOR	4. BASE	4. ANODE	

5. EMITTER

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DOCUMENT NUMBER: 98AON11127D

PAGE 2 OF 2

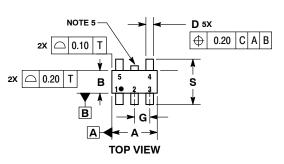
ED STYLES 3-9. REQ. BY D. BARLOW ED NOMINAL VALUES AND UPDATED GENERIC MARKING DIAGRAM. REQ. ONG XIAO ATED DIMENSIONS D, E, AND HE. REQ. BY J. LETTERMAN.	11 NOV 2003 27 MAY 2005 20 MAR 2013
ONG XIAO	
ATED DIMENSIONS D, E, AND HE. REQ. BY J. LETTERMAN.	20 MAR 2013

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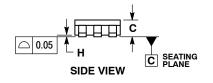


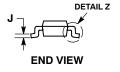
TSOP-5 **CASE 483 ISSUE N**

DATE 12 AUG 2020









NOTES:

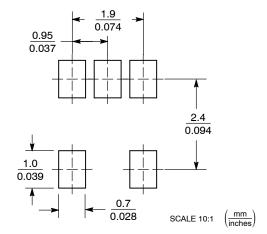
- DIMENSIONING AND TOLERANCING PER ASME
- CONTROLLING DIMENSION: MILLIMETERS.
 MAXIMUM LEAD THICKNESS INCLUDES LEAD FINISH
 THICKNESS. MINIMUM LEAD THICKNESS IS THE
 MINIMUM THICKNESS OF BASE MATERIAL.
- MINIMUM I HICKNESS OF BASE MAI EHIAL.

 DIMENSIONS A AND B DO NOT INCLUDE MOLD
 FLASH, PROTRUSIONS, OR GATE BURRS. MOLD
 FLASH, PROTRUSIONS, OR GATE BURRS SHALL NOT
 EXCEED 0.15 PER SIDE. DIMENSION A.

 OPTIONAL CONSTRUCTION: AN ADDITIONAL
- TRIMMED LEAD IS ALLOWED IN THIS LOCATION. TRIMMED LEAD NOT TO EXTEND MORE THAN 0.2 FROM BODY.

	MILLIMETERS			
DIM	MIN MAX			
Α	2.85	3.15		
В	1.35	1.65		
С	0.90	1.10		
D	0.25	0.50		
G	0.95 BSC			
Н	0.01	0.10		
J	0.10	0.26		
K	0.20	0.60		
М	0° 10°			
S	2.50	3.00		

SOLDERING FOOTPRINT*



^{*}For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

GENERIC MARKING DIAGRAM*





XXX = Specific Device Code XXX = Specific Device Code

= Assembly Location = Date Code

= Year = Pb-Free Package

= Work Week W

= Pb-Free Package

(Note: Microdot may be in either location)

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot " ■", may or may not be present.

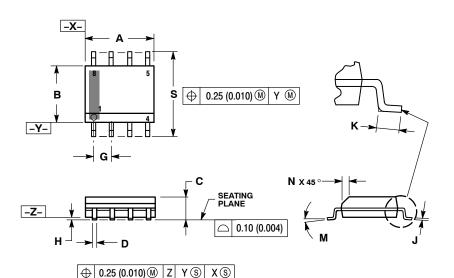
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SOIC-8 NB CASE 751-07 **ISSUE AK**

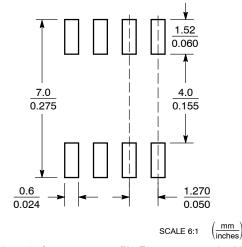
DATE 16 FEB 2011



- NOTES:
 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982. CONTROLLING DIMENSION: MILLIMETER.
- DIMENSION A AND B DO NOT INCLUDE MOLD PROTRUSION.
- MAXIMUM MOLD PROTRUSION 0.15 (0.006) PER SIDE
- DIMENSION D DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.127 (0.005) TOTAL IN EXCESS OF THE D DIMENSION AT MAXIMUM MATERIAL CONDITION.
- 751-01 THRU 751-06 ARE OBSOLETE. NEW STANDARD IS 751-07.

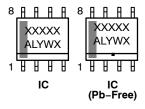
	MILLIMETERS		INC	HES
DIM	MIN	MAX	MIN	MAX
Α	4.80	5.00	0.189	0.197
В	3.80	4.00	0.150	0.157
C	1.35	1.75	0.053	0.069
D	0.33	0.51	0.013	0.020
G	1.27 BSC		0.050 BSC	
Н	0.10	0.25	0.004	0.010
7	0.19	0.25	0.007	0.010
K	0.40	1.27	0.016	0.050
М	0 °	8 °	0 °	8 °
N	0.25	0.50	0.010	0.020
S	5.80	6.20	0.228	0.244

SOLDERING FOOTPRINT*



^{*}For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

GENERIC MARKING DIAGRAM*



XXXXX = Specific Device Code = Assembly Location = Wafer Lot

= Year = Work Week = Pb-Free Package XXXXXX AYWW AYWW H \mathbb{H} Discrete **Discrete** (Pb-Free)

XXXXXX = Specific Device Code = Assembly Location Α = Year

ww = Work Week = Pb-Free Package

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "•", may or may not be present. Some products may not follow the Generic Marking.

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SOIC-8 NB CASE 751-07 ISSUE AK

DATE 16 FEB 2011

STYLE 1: PIN 1. EMITTER 2. COLLECTOR 3. COLLECTOR 4. EMITTER 5. EMITTER 6. BASE 7. BASE 8. EMITTER	STYLE 2: PIN 1. COLLECTOR, DIE, #1 2. COLLECTOR, #1 3. COLLECTOR, #2 4. COLLECTOR, #2 5. BASE, #2 6. EMITTER, #2 7. BASE, #1 8. EMITTER, #1	STYLE 3: PIN 1. DRAIN, DIE #1 2. DRAIN, #1 3. DRAIN, #2 4. DRAIN, #2 5. GATE, #2 6. SOURCE, #2 7. GATE, #1 8. SOURCE, #1	STYLE 4: PIN 1. ANODE 2. ANODE 3. ANODE 4. ANODE 5. ANODE 6. ANODE 7. ANODE 8. COMMON CATHODE
STYLE 5: PIN 1. DRAIN 2. DRAIN 3. DRAIN 4. DRAIN 5. GATE 6. GATE 7. SOURCE 8. SOURCE	7. BASE, #1 8. EMITTER, #1 STYLE 6: PIN 1. SOURCE 2. DRAIN 3. DRAIN 4. SOURCE 5. SOURCE 6. GATE 7. GATE 8. SOURCE	STYLE 7: PIN 1. INPUT 2. EXTERNAL BYPASS 3. THIRD STAGE SOURCE 4. GROUND 5. DRAIN 6. GATE 3 7. SECOND STAGE Vd 8. FIRST STAGE Vd	STYLE 8: PIN 1. COLLECTOR, DIE #1 2. BASE, #1 3. BASE, #2
STYLE 9: PIN 1. EMITTER, COMMON 2. COLLECTOR, DIE #1 3. COLLECTOR, DIE #2 4. EMITTER, COMMON 5. EMITTER, COMMON 6. BASE, DIE #2 7. BASE, DIE #1 8. EMITTER, COMMON	STYLE 10: PIN 1. GROUND 2. BIAS 1 3. OUTPUT 4. GROUND 5. GROUND 6. BIAS 2 7. INPUT 8. GROUND	STYLE 11: PIN 1. SOURCE 1 2. GATE 1 3. SOURCE 2 4. GATE 2 5. DRAIN 2 6. DRAIN 2 7. DRAIN 1 8. DRAIN 1	STYLE 12: PIN 1. SOURCE 2. SOURCE 3. SOURCE 4. GATE 5. DRAIN 6. DRAIN 7. DRAIN 8. DRAIN
STYLE 13: PIN 1. N.C. 2. SOURCE 3. SOURCE 4. GATE 5. DRAIN 6. DRAIN 7. DRAIN 8. DRAIN	STYLE 14: PIN 1. N-SOURCE 2. N-GATE 3. P-SOURCE 4. P-GATE 5. P-DRAIN 6. P-DRAIN 7. N-DRAIN 8. N-DRAIN	STYLE 15: PIN 1. ANODE 1 2. ANODE 1 3. ANODE 1 4. ANODE 1 5. CATHODE, COMMON 6. CATHODE, COMMON 7. CATHODE, COMMON 8. CATHODE, COMMON	STYLE 16: PIN 1. EMITTER, DIE #1 2. BASE, DIE #1 3. EMITTER, DIE #2 4. BASE, DIE #2 5. COLLECTOR, DIE #2 6. COLLECTOR, DIE #2 7. COLLECTOR, DIE #1 8. COLLECTOR, DIE #1
STYLE 17: PIN 1. VCC 2. V2OUT 3. V1OUT 4. TXE 5. RXE 6. VEE 7. GND 8. ACC	STYLE 18: PIN 1. ANODE 2. ANODE 3. SOURCE 4. GATE 5. DRAIN 6. DRAIN 7. CATHODE 8. CATHODE	STYLE 19: PIN 1. SOURCE 1 2. GATE 1 3. SOURCE 2 4. GATE 2 5. DRAIN 2 6. MIRROR 2 7. DRAIN 1 8. MIRROR 1	STYLE 20: PIN 1. SOURCE (N) 2. GATE (N) 3. SOURCE (P) 4. GATE (P) 5. DRAIN 6. DRAIN 7. DRAIN 8. DRAIN
5. RXE 6. VEE 7. GND 8. ACC STYLE 21: PIN 1. CATHODE 1 2. CATHODE 2 3. CATHODE 3 4. CATHODE 4 5. CATHODE 5 6. COMMON ANODE 7. COMMON ANODE 8. CATHODE 6	STYLE 22: PIN 1. I/O LINE 1 2. COMMON CATHODE/VCC 3. COMMON CATHODE/VCC 4. I/O LINE 3 5. COMMON ANODE/GND 6. I/O LINE 4 7. I/O LINE 5 8. COMMON ANODE/GND	STYLE 23: PIN 1. LINE 1 IN 2. COMMON ANODE/GND 3. COMMON ANODE/GND 4. LINE 2 IN 5. LINE 2 OUT 6. COMMON ANODE/GND 7. COMMON ANODE/GND 8. LINE 1 OUT	STYLE 24: PIN 1. BASE 2. EMITTER 3. COLLECTOR/ANODE 4. COLLECTOR/ANODE 5. CATHODE 6. CATHODE 7. COLLECTOR/ANODE 8. COLLECTOR/ANODE
STYLE 25: PIN 1. VIN 2. N/C 3. REXT 4. GND 5. IOUT 6. IOUT 7. IOUT 8. IOUT	STYLE 26: PIN 1. GND 2. dv/dt 3. ENABLE 4. ILIMIT 5. SOURCE 6. SOURCE 7. SOURCE 8. VCC	STYLE 27: PIN 1. ILIMIT 2. OVLO 3. UVLO 4. INPUT+ 5. SOURCE 6. SOURCE 7. SOURCE 8. DRAIN	STYLE 28: PIN 1. SW_TO_GND 2. DASIC_OFF 3. DASIC_SW_DET 4. GND 5. V_MON 6. VBULK 7. VBULK 8. VIN
STYLE 29: PIN 1. BASE, DIE #1 2. EMITTER, #1 3. BASE, #2 4. EMITTER, #2 5. COLLECTOR, #2 6. COLLECTOR, #2 7. COLLECTOR, #1 8. COLLECTOR, #1	STYLE 30: PIN 1. DRAIN 1 2. DRAIN 1 3. GATE 2 4. SOURCE 2 5. SOURCE 1/DRAIN 2 6. SOURCE 1/DRAIN 2 7. SOURCE 1/DRAIN 2 8. GATE 1		

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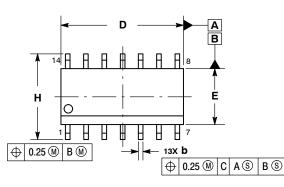
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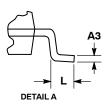


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SOIC-14 NB CASE 751A-03 ISSUE L

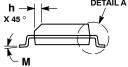
DATE 03 FEB 2016







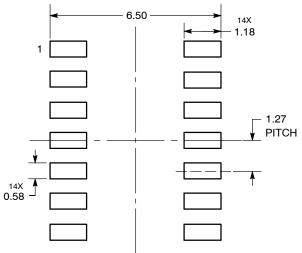




- NOTES:
 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
 CONTROLLING DIMENSION: MILLIMETERS.
- DIMENSION b DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE PROTRUSION SHALL BE 0.13 TOTAL IN EXCESS OF AT
- MAXIMUM MATERIAL CONDITION.
 DIMENSIONS D AND E DO NOT INCLUDE MOLD PROTRUSIONS.
- 5. MAXIMUM MOLD PROTRUSION 0.15 PER SIDE

	MILLIMETERS		INC	HES
DIM	MIN	MAX	MIN	MAX
Α	1.35	1.75	0.054	0.068
A1	0.10	0.25	0.004	0.010
АЗ	0.19	0.25	0.008	0.010
b	0.35	0.49	0.014	0.019
D	8.55	8.75	0.337	0.344
Е	3.80	4.00	0.150	0.157
œ	1.27 BSC		0.050 BSC	
Н	5.80	6.20	0.228	0.244
h	0.25	0.50	0.010	0.019
L	0.40	1.25	0.016	0.049
М	0 °	7°	0 °	7 °

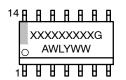
SOLDERING FOOTPRINT*



DIMENSIONS: MILLIMETERS

C SEATING PLANE

GENERIC MARKING DIAGRAM*



XXXXX = Specific Device Code Α = Assembly Location

WL = Wafer Lot Υ = Year WW = Work Week G = Pb-Free Package

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator. "G" or microdot " ■". may or may not be present.

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^{*}For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

SOIC-14 CASE 751A-03 ISSUE L

DATE 03 FEB 2016

STYLE 1: PIN 1. COMMON CATHODE 2. ANODE/CATHODE 3. ANODE/CATHODE 4. NO CONNECTION 5. ANODE/CATHODE 6. NO CONNECTION 7. ANODE/CATHODE 8. ANODE/CATHODE 9. ANODE/CATHODE 10. NO CONNECTION 11. ANODE/CATHODE 12. ANODE/CATHODE 13. NO CONNECTION 14. COMMON ANODE	STYLE 2: CANCELLED	STYLE 3: PIN 1. NO CONNECTION 2. ANODE 3. ANODE 4. NO CONNECTION 5. ANODE 6. NO CONNECTION 7. ANODE 8. ANODE 9. ANODE 10. NO CONNECTION 11. ANODE 12. ANODE 13. NO CONNECTION 14. COMMON CATHODE	STYLE 4: PIN 1. NO CONNECTION 2. CATHODE 3. CATHODE 4. NO CONNECTION 5. CATHODE 6. NO CONNECTION 7. CATHODE 8. CATHODE 9. CATHODE 10. NO CONNECTION 11. CATHODE 12. CATHODE 13. NO CONNECTION 14. COMMON ANODE
STYLE 5: PIN 1. COMMON CATHODE 2. ANODE/CATHODE 3. ANODE/CATHODE 4. ANODE/CATHODE 5. ANODE/CATHODE 6. NO CONNECTION 7. COMMON ANODE 8. COMMON CATHODE 9. ANODE/CATHODE 10. ANODE/CATHODE 11. ANODE/CATHODE 12. ANODE/CATHODE 13. NO CONNECTION 14. COMMON ANODE	STYLE 6: PIN 1. CATHODE 2. CATHODE 3. CATHODE 4. CATHODE 5. CATHODE 6. CATHODE 7. CATHODE 8. ANODE 9. ANODE 10. ANODE 11. ANODE 12. ANODE 13. ANODE 14. ANODE	STYLE 7: PIN 1. ANODE/CATHODE 2. COMMON ANODE 3. COMMON CATHODE 4. ANODE/CATHODE 5. ANODE/CATHODE 6. ANODE/CATHODE 7. ANODE/CATHODE 8. ANODE/CATHODE 9. ANODE/CATHODE 10. ANODE/CATHODE 11. COMMON CATHODE 12. COMMON ANODE 13. ANODE/CATHODE 14. ANODE/CATHODE	STYLE 8: PIN 1. COMMON CATHODE 2. ANODE/CATHODE 3. ANODE/CATHODE 4. NO CONNECTION 5. ANODE/CATHODE 6. ANODE/CATHODE 7. COMMON ANODE 8. COMMON ANODE 9. ANODE/CATHODE 10. ANODE/CATHODE 11. NO CONNECTION 12. ANODE/CATHODE 13. ANODE/CATHODE 14. COMMON CATHODE

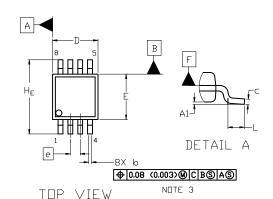
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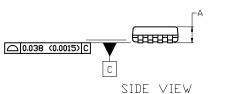
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Micro8 CASE 846A-02 ISSUE K

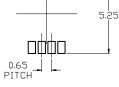
DATE 16 JUL 2020







-8X 0.80



RECOMMENDED MOUNTING FOOTPRINT

NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 2009.
- CONTROLLING DIMENSION: MILLIMETERS
- DIMENSION 6 DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE PROTRUSION SHALL BE 0.10 mm IN EXCESS OF MAXIMUM MATERIAL CONDITION.
- DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH, PROTRUSION OR GATE BURRS. MOLD FLASH, PROTRUSIONS, OR GATE BURRS SHALL NOT EXCEED 0.15 mm PER SIDE. DIMENSION E DOES NOT INCLUDE INTERLEAD FLASH OR PROTRUSION. INTERLEAD FLASH OR PROTRUSION SHALL NOT EXCEED 0.25 mm PER SIDE. DIMENSIONS D AND E ARE DETERMINED AT DATUM F.
- DATUMS A AND B ARE TO BE DETERMINED AT DATUM F.
- A1 IS DEFINED AS THE VERTICAL DISTANCE FROM THE SEATING PLANE TO THE LOWEST POINT ON THE PACKAGE BODY.

DIM	MILLIMETERS		
	MIN.	N□M.	MAX.
Α	-	-	1.10
A1	0.05	0.08	0.15
b	0.25	0.33	0.40
С	0.13	0.18	0.23
D	2.90	3.00	3.10
E	2.90	3.00	3.10
е	0.65 BSC		
HE	4.75	4.90	5.05
L	0.40	0.55	0.70

GENERIC MARKING DIAGRAM*



XXXX = Specific Device Code Α = Assembly Location

Υ = Year W = Work Week = Pb-Free Package

(Note: Microdot may be in either location)

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "■", may or may not be present. Some products may not follow the Generic Marking.

STYLE 1:	STYLE 2:	STYLE 3:
PIN 1. SOURCE	PIN 1. SOURCE 1	PIN 1. N-SOURCE
2. SOURCE	2. GATE 1	2. N-GATE
SOURCE	SOURCE 2	P-SOURCE
4. GATE	4. GATE 2	4. P-GATE
5. DRAIN	5. DRAIN 2	5. P-DRAIN
6. DRAIN	6. DRAIN 2	6. P-DRAIN
7. DRAIN	7. DRAIN 1	7. N-DRAIN
8. DRAIN	8. DRAIN 1	8. N-DRAIN

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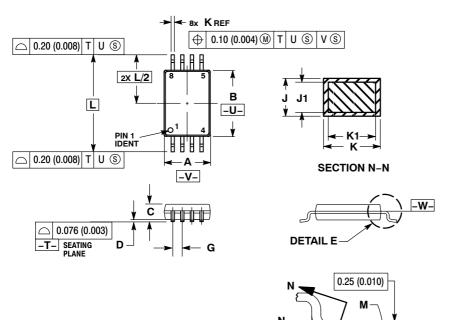


TSSOP-8 CASE 948S-01 ISSUE C

-F→

DETAIL E

DATE 20 JUN 2008



NOTES:

- DIMENSIONING AND TOLERANCING PER ANSI
- 714.5M, 1982.

 2. CONTROLLING DIMENSION: MILLIMETER.

 3. DIMENSION A DOES NOT INCLUDE MOLD FLASH.
 PROTRUSIONS OR GATE BURRS. MOLD FLASH OR GATE BURRS SHALL NOT EXCEED 0.15 (0.006) PER SIDE.
- (0.006) PEH SIDE.

 4. DIMENSION B DOES NOT INCLUDE INTERLEAD FLASH OR PROTRUSION. INTERLEAD FLASH OR PROTRUSION SHALL NOT EXCEED 0.25 (0.010) PER SIDE
- 5. TERMINAL NUMBERS ARE SHOWN FOR REFERENCE ONLY.
- DIMENSION A AND B ARE TO BE DETERMINED AT DATUM PLANE -W-.

	MILLIMETERS		INCHES	
DIM	MIN	MAX	MIN	MAX
Α	2.90	3.10	0.114	0.122
В	4.30	4.50	0.169	0.177
С		1.10		0.043
D	0.05	0.15	0.002	0.006
F	0.50	0.70	0.020	0.028
G	0.65 BSC		0.026 BSC	
J	0.09	0.20	0.004	0.008
J1	0.09	0.16	0.004	0.006
K	0.19	0.30	0.007	0.012
K1	0.19	0.25	0.007	0.010
L	6.40 BSC		0.252 BSC	
М	0°	8°	0°	8°

GENERIC MARKING DIAGRAM*



XXX = Specific Device Code = Assembly Location Α

= Year WW = Work Week = Pb-Free Package

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot " ■", may or may not be present.

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ISSUE	REVISION	DATE
0	RELEASED FOR PRODUCTION.	18 APR 2000
Α	ADDED MARKING DIAGRAM INFORMATION. REQ. BY V. BASS.	13 JAN 2006
В	CORRECTED MARKING DIAGRAM PIN 1 LOCATION AND MARKING. REQ. BY C. REBELLO.	13 MAR 2006
С	REMOVED EXPOSED PAD VIEW AND DIMENSIONS P AND P1. CORRECTED MARKING INFORMATION. REQ. BY C. REBELLO.	20 JUN 2008
		-

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